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PARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 015681-088003

Mark W. Miles

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	AA	5	1	6	8	4	0	6	12/01/92	Nelson			
	AB	5	5	7	9	1	4	9	11/26/96	Moret et al.			
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	AE	2	5	3	4	8	4	6	12/19/50	Ambrose et al.			
	AF	3	4	3	9	9	7	3	04/22/69	Paul et al.			
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AR	Aratani, et al., "Process and Design Considerations for Surface Micromachined Beams for a Tuneable Inter-
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	CA	5	0	2	2	7	4	5	06/11/91	Zahowski			
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